

<b>Notice of References Cited</b>	Application/Control No. 10/529,655		Applicant(s)/Patent Under Reexamination SCANLAN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1 033 401 A2	09-2000		Dumas et al	
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Altman et al (Science, 10/4/96, 274:94-96)			
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